

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/695,810	CHANG ET AL.	
Examiner	Art Unit	
Hana A. Sanei	2879	

SEARCHED						
Class	Subclass	Date	Examiner			
445	23,24,25	7/26/2005	H.S.			
156	153,154	7/26/2005	H.S.			
	:					

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
For Text Search see attached "Search History	7/26/2005	H.S.		
Consulted Jeff Aftergut for search	7/26/2005	H.S.		
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